

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10576195	HAYASHIDA ET AL.
	<b>Examiner</b> /Susan W Berman/	<b>Art Unit</b> 1796

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
522	83	7-19-08	sb
522	96	7-19-08	sb
522	97	7-19-08	sb
522	82, 83, 96, 97	7-27-09	sb
523	205, 209	7-27-09	sb
524	430, 431, 432, 433, 420, 493	7-27-009	sb

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor	7-19-08	sb
reviewed PCT seach	7-19-08	sb
reviewed chinese search and opinion	7-19-08	sb
reviewed additional search submitted by applicant	7-19-08	sb
EAST (see printout)	7-19-08	sb
EAST update- see printout	7-27-09	sb
EAST Interference- see printout	7-27-09	sb

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
all above	all above	7-27-09	sb